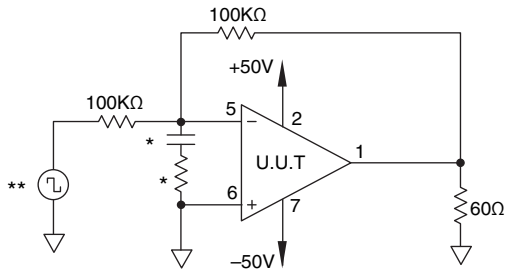
Table 4 Group A Inspection

SG	PARAMETER	SYMBOL	TEMP.	POWER	TEST CONDITIONS	MIN	MAX	UNITS
1	Quiescent Current	I_Q	25°C	±150V	V_{IN} = 0, A_V = 100		8.5	mA
1	Input Offset Voltage	V_{OS}	25°C	±150V	V_{IN} = 0, A_V = 100		3	mV
1	Input Offset Voltage	V_{OS}	25°C	±15V	V_{IN} = 0, A_V = 100		5.7	mV
1	Input Bias Current, +IN	$+I_B$	25°C	±150V	V_{IN} = 0		50	pA
1	Input Bias Current, –IN	$–I_B$	25°C	±150V	V_{IN} = 0		50	pA
1	Input Offset Current	I_{OS}	25°C	±150V	V_{IN} = 0		50	pA
3	Quiescent Current	I_Q	–55°C	±150V	V_{IN} = 0, A_V = 100		10	mA
3	Input Offset Voltage	V_{OS}	–55°C	±150V	V_{IN} = 0, A_V =100		5	mV
3	Input Offset Voltage	V_{OS}	–55°C	±15V	V_{IN} = 0, A_V = 100		7.7	mV
3	Input Bias Current, +IN	$+I_B$	–55°C	±150V	V_{IN} = 0		50	pA
3	Input BiasCurrent, –IN	$–I_B$	–55°C	±150V	V_{IN} = 0		50	pA
3	Input Offset Current	I_{OS}	–55°C	±150V	V_{IN} = 0		50	pA
2	Quiescent Current	I_Q	125°C	±150V	V_{IN} = 0, A_V = 100		10	mA
2	Input Offset Voltage	V_{OS}	125°C	±150V	V_{IN} = 0, A_V = 100		5.5	mV
2	Input Offset Voltage	V_{OS}	125°C	±15V	V_{IN} = 0, A_V = 100		8.2	mV
2	Input Bias Current, +IN	$+I_B$	125°C	±150V	V_{IN} = 0		10	nA
2	Input Bias Current, –IN	$–I_B$	125°C	±150V	V_{IN} = 0		10	nA
2	Input Offset Current	I_{OS}	125°C	±150V	V_{IN} = 0		10	nA
4	Output Voltage, I_O = 75mA	V_O	25°C	±85V	R_L = 1K	75		V
4	Output Voltage, I_O = 29mA	V_O	25°C	±150V	R_L = 5K	145		V
4	Current Limits	I_{CL}	25°C	±30V	R_L = 100Ω	75	125	mA
4	Stability/Noise	E_N	25°C	±150V	R_L = 5K, A_V = 1, C_L = 10nF		1	mV
4	Slew Rate	SR	25°C	±150V	R_L = 5K	20	80	V/µs
4	Open Loop Gain	A_{OL}	25°C	±150V	R_L = 5K, F = 10Hz	96		dB
4	Common Mode Rejection	CMR	25°C	±32.5V	R_L = 5K, F = DC, V_{CM} = ±22.5V	90		dB
6	Output Voltage, I_O = 40mA	V_O	–55°C	±45V	R_L = 1K	40		V
6	Output Voltage, I_O = 29mA	V_O	–55°C	±150V	R_L = 5K	145		V
6	Stability/Noise	E_N	–55°C	±150V	R_L = 5K, A_V = 1, C_L = 10nF		1	mV
6	Slew Rate	SR	–55°C	±150V	R_L = 5K	20	80	V/µs
6	Open Loop Gain	A_{OL}	–55°C	±150V	R_L = 5K, F = 10Hz	96		dB
6	Common Mode Rejection	CMR	–55°C	±32.5V	R_L = 5K, F = DC, V_{CM} = ±22.5V	90		dB
5	Output Voltage, I_O = 40mA	V_O	125°C	±45V	R_L = 1K	40		V
5	Output Voltage, I_O = 29mA	V_O	125°C	±150V	R_L = 5K	145		V
5	Stability/Noise	E_N	125°C	±150V	R_L = 5K, A_V = 1, C_L = 10nF		1	mV
5	Slew Rate	SR	125°C	±150V	R_L = 5K	20	80	V/µs
5	Open Loop Gain	A_{OL}	125°C	±150V	R_L = 5K, F = 10Hz	96		dB
5	Common Mode Rejection	CMR	125°C	±32.5V	R_L = 5K, F = DC, V_{CM} = ±22.5V	90		dB

BURN IN CIRCUIT



* These components are used to stabilize device due to poor high frequency characteristics of burn in board.

** Input signals are calculated to result in internal power dissipation of approximately 2.1W at case temperature = 125°C.

NEED TECHNICAL HELP? CONTACT APEX SUPPORT!

For all Apex Microtechnology product questions and inquiries, call toll free 800-546-2739 in North America.
For inquiries via email, please contact apex.support@apexanalog.com.
International customers can also request support by contacting their local Apex Microtechnology Sales Representative.
To find the one nearest to you, go to www.apexanalog.com